

AMENDMENTS TO THE SPECIFICATION:

Kindly amend the specification as follows:

Please replace the paragraph beginning on Line 9 of Page 10 with the following amended paragraph:

In FIG. 1 the conveyor 3 is arranged to move the carriers 2 from left to right towards the test probe head 1. The carriers 2 are introduced onto the conveyor 3 by means of an input elevator 4 that receives the carriers 2 bearing the leadframe(s). Any conventional trim and form loading apparatus can be coupled to the apparatus of the present invention. Such a machine will ensure that the leadframes are correctly loaded on the carrier and that all the leads are cut and are of the correct number before being fed into the test process. As will be explained further below a single carrier 2 may carry one or more leadframes. The input elevator 4 raises the carrier 2 until it is at the same level as the conveyor 3. A kicker 5 then functions to transfer a carrier 2 from the elevator 4 onto the conveyor 3. The carrier 2 may be provided with electronically readable carrier identification means 91 which may be read by a reader 6 located adjacent the kicker 5 such that the reader 6 may then send a signal to a control means (not shown) to indicate that a particular carrier is entering the apparatus. The identification means 91 may, for example, include information regarding the number of leadframes on the carrier 2 and the configuration of the semiconductor devices that is supplied to the test probe head 1 so that when the carrier 2 reaches the test probe head 1 an appropriate test probe configuration is selected for testing the devices on that particular carrier 2.